

March 2008

# **FDS9933BZ**

# Dual P-Channel 2.5V Specified PowerTrench® MOSFET

-20V, -4.9A, 46m $\Omega$ 

#### **Features**

- Max  $r_{DS(on)} = 46m\Omega$  at  $V_{GS} = -4.5V$ ,  $I_D = -4.9A$
- Max  $r_{DS(on)} = 69m\Omega$  at  $V_{GS} = -2.5V$ ,  $I_D = -4.0A$
- Low gate charge (11nC typical).
- High performance trench technology for extremely low r<sub>DS(on)</sub>.
- HBM ESD protection level >3kV (Note 3).
- RoHS Compliant



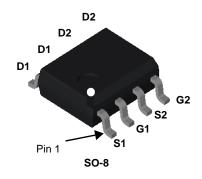
## **General Description**

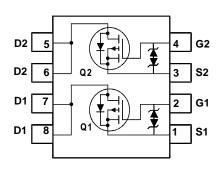
These P-Channel 2.5V specified MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

These devices are well suited for portable electronics applications: load switching and power management, battery charging and protection circuits.

## **Applications**

- Battery Charging
- Load Switching





## MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			-20	V
V <sub>GS</sub>	Gate to Source Voltage			±12	V
1	Drain Current -Continuous	T <sub>A</sub> = 25°C	(Note 1a)	-4.9	^
'D	-Pulsed			-30	Α
D	Power Dissipation		(Note 1a)	1.6	w
$P_{D}$	Power Dissipation		(Note 1b)	0.9	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tempera	ture Range		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	40	°C/W
$R_{\thetaJA}$	Thermal Resistance, Junction to Ambient (Note 1a)	78	C/VV

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS9933BZ	FDS9933BZ	SO-8	330mm	12mm	2500 units

# Electrical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250μA, referenced to 25°C		-9		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16V, \ V_{GS} = 0V$			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 12V$ , $V_{DS} = 0V$			±10	μΑ

### On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.9	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = -250μA, referenced to 25°C		3		mV/°C
		$V_{GS} = -4.5V, I_D = -4.9A$		38	46	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = -2.5V, I_D = -4.0A$		54	69	mΩ
, ,		$V_{GS} = -4.5V$ , $I_D = -4.9A$ , $T_J = 125$ °C		52	67	
g <sub>FS</sub>	Forward Transconductance	$V_{DD} = -10V, I_{D} = -4.9A$		17		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	10)/ )/	740	985	pF
Coss	Output Capacitance	$V_{DS} = -10V, V_{GS} = 0V,$ f = 1MHz	160	215	pF
$C_{rss}$	Reverse Transfer Capacitance	1 - 111112	145	220	pF

## **Switching Characteristics**

	•				
t <sub>d(on)</sub>	Turn-On Delay Time	.,	6.7	7 14	ns
t <sub>r</sub>	Rise Time	$V_{DD} = -10V, I_{D} = -4.9A,$ $V_{GS} = -4.5V, R_{GEN} = 6\Omega$	9.3	3 19	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = -4.5 V, R <sub>GEN</sub> = 012	59	95	ns
t <sub>f</sub>	Fall Time		47	7 76	ns
$Q_g$	Total Gate Charge	$V_{DD} = -10V, I_{D} = -4.9A$	11	15	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>GS</sub> = -4.5V	1.4	1	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		3.7	7	nC

## **Drain-Source Diode Characteristics**

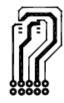
I <sub>S</sub>	Maximum continuous Drain-Sourse Diode Forward Current			-1.3	Α
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_{S} = -1.3A$ (Note 2)	-0.8	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = -4.9A, di/dt = 100A/μs	46	74	ns
Q <sub>rr</sub>	Reverse Recovery Charge	1 <sub>F</sub> = -4.9A, α//αt = 100A/μS	23	37	nC

#### NOTES

<sup>. . . .</sup> R<sub>0JA</sub> is determined with the device mounted on a  $1\text{in}^2$  pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a) 78°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b) 135°C/W when mounted on a minimun pad

- 2. Pulse Test: Pulse Width <  $300\mu s$ , Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

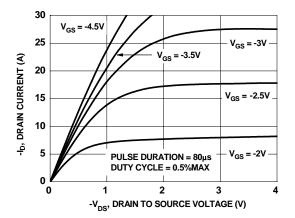
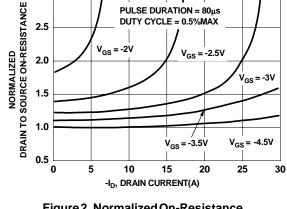


Figure 1. On-Region Characteristics



3.0

Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

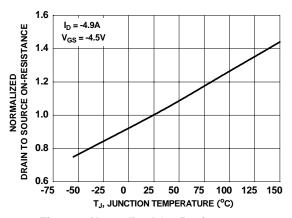


Figure 3. Normalized On-Resistance vs Junction Temperature

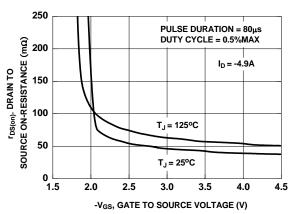


Figure 4. On-Resistance vs Gate to Source Voltage

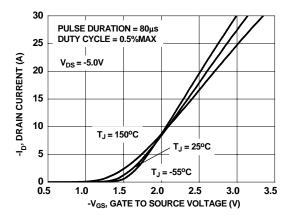


Figure 5. Transfer Characteristics

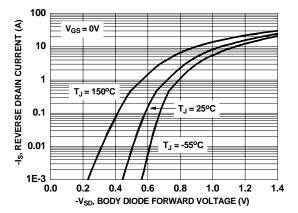


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

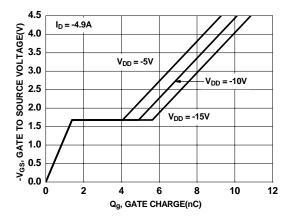


Figure 7. Gate Charge Characteristics

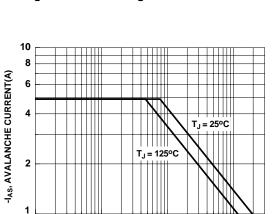


Figure 9. Unclamped Inductive Switching Capability

t<sub>AV</sub>, TIME IN AVALANCHE(ms)

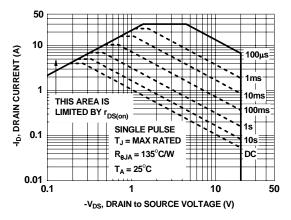


Figure 11. Forward Bias Safe Operating Area

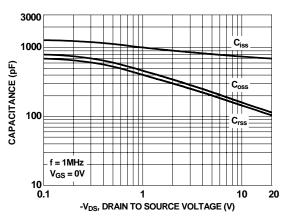


Figure 8. Capacitance vs Drain to Source Voltage

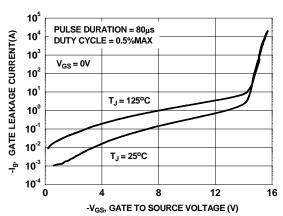


Figure 10. Gate Leakage Current vs Gate to Sourse Voltage

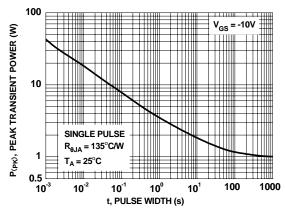


Figure 12. Single Pulse Maximum Power Dissipation

0.01

30

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

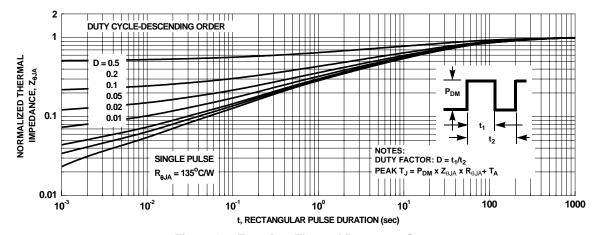


Figure 13. Transient Thermal Response Curve





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